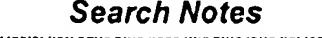


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/623,692	TAKEUCHI ET AL.
Examiner	Art Unit	
James Phan	2872	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See "Search Notes"		3/06	JP-